# TS IEC 62804-1:2015-08

## Photovoltaic (PV) modules - Test methods for detection of potential-induced degradation – Part 1: Crystalline silicon

| | |
|---|---|
| **Reference No.:** | 5018237-3972-0001 |
| **Applicant:** | Sharp Electronics (Europe) LTD<br>4 Furzeground Way, UXBRIDGE (MIDDLESEX),<br>United Kingdom |
| **Product:** | Crystalline silicon Photovoltaic (PV)-Modules |
| **Type:** | NU-RCXXX<br>NU-RDXXX<br>ND-RCXXX<br>XXX in the type number replaces the real output of the modules at STC, rounded off in steps of five.<br>195 – 310 W |
| **Manufacturer:** | Sharp Electronics (Europe) LTD |
| **Standard:** | TS IEC 62804-1:2015-08 |

**Test conditions:**

| | |
|---|---|
| Testing time: | 96 h |
| Chamber temperature: | 60°C |
| Relative Humidity: | 85 % |
| Potential to ground: | - 1000 V |

**Pass criteria:**

| | |
|---|---|
| Power degradation: | < 5% |
| Dry Insulation: | > 40 MΩm² |
| Wet insulation: | > 40 MΩm² |

# TS IEC 62804-1:2015-08

## Photovoltaic (PV) modules - Test methods for detection of potential-induced degradation – Part 1: Crystalline silicon

**Summary of test results:**

| | | |
|---|---|---|
| Maximum power degradation: | required | < 5 % |
| | measured | max. 0.80 % |
| | The measured degradation is below the allowed degradation. | |
| Dry insulation resistance: | required | 24.00 MΩ |
| | measured | >500 MΩ |
| | The measured dry insulation resistance is above the limit. | |
| Wet insulation resistance: | required | 24.00 MΩ |
| | measured | >500 MΩ |
| | The measured wet insulation resistance is above the limit. | |
| Visual inspection: | No findings | |

The complete test results are given in Test Report No.: 217376-ET2-1

VDE Prüf- und Zertifizierungsinstitut GmbH
ET2, Photovoltaik, Module und Systeme,
Erneuerbare Energien und Leistungselektronik

Arnd Roth

Jürgen Bärwinkel